# Design Flows for Optimal Power Designs Or <br> Toward Optimal Power Efficiency in Digital IC's 

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## Energy Efficiency of Contemporary Digital ICs

- Much of the concern these days in energy efficiency is seemingly at higher levels ... which is good
- But, how much energy is wasted at the synthesis/physical design level?
$>$ At least 25\% in dynamic power
$>$ At least $50 \%$ in total power
- Now that's significant!


## Why So Much Energy Waste?

- Designers use the same library for both synthesis and physical design (place and route)
$>$ Very bad idea
$>$ The library that gives the best synthesis results is not the library that will give you the best post physical design results (power, delay)
- Ironically, the physical cell library can be very small, greatly reducing library upkeep
> My observations are that cell libraries are like ant or rodent traps ... once something gets in, it never gets out ...


## Why So Much Energy Waste? (cont'd)

- You have to make sure that each micron (ok, nm) of transistor size is actually doing something critical
> Need an optimal and efficient optimal gate size selector, before physical design, after initial physical design and after later physical design
$>$ And of course you have to have appropriate drive strengths and beta ratios for the physical library cells.
- You won't want to use a $\mathrm{V}_{T}$ any higher than absolutely necessary for any cell


## Toward Optimal Power Efficiency

- Major elements:

1. Employ something that approaches an optimal synthesis library (very different from an optimal physical library)
2. Employ something that approaches an optimal physical library
3. Aim at near-optimal arithmetic networks (and thus must nail down THE way to implement a Full Adder (FA))
4. Optimal continuous gate size selection
5. Near-optimal discrete gate size selection
6. Near-optimal $V_{T}$ selection

- Tie-in with placement is important


## Optimal Continuous Gate Size Selection

- First globally optimal, robust Lagrangian relaxation-based continuous gate sizer (Forge)
- Extremely accurate cell delay models are based on the actual .lib cell characterization data
- The delay we get is the same delay reported by leading STAs
- Two modes of operation
$>$ Generates the global minimum power for any desired delay
$>$ First generates the fast possible design, then the lowest power design, and finally a set of (e.g., 10-20) delay points in between, each with minimum power


## Near-Optimal Discrete Gate Size Selection

- The continuous-sized solutions are then converted to library-based, discrete gate size solutions
- Very first discrete approach to obtain results CLOSE to the global minimum continuous results
- First discrete gate sizer that nearly optimally assigns Vt's among the selections available in the library
- Handles multiple clock domains
- Handles commercial chips today, millions of cells
- Applicable to ANY structural (Verilog) netlist at any point in design flow
> Pre layout
> Post layout
$>$ With or without wire load model
$>$ With or without actual wiring parasitics


## Results Summary

- Based on several large commercial blocks, we obtain > 35\% power reduction for the same delay vs. leading EDA tools
$\gg 50 \%$ leakage reduction for the same delay
$>$ Integrated with leading synthesis tools


## Discrete Sizing - 300MHz Industrial Block



- 65 nm process $-125^{\circ} \mathrm{C} 0.9 \mathrm{~V}$ SVT
- Total gates : 46,132 (excluding registers)


## Discrete Sizing - 300MHz block (Zoomed)



- Average area increment over continuous sizing $1.55 \%$


## Discrete Sizing - 900MHz block



- Total gates : 49,614 (excluding registers)


## Discrete Sizing - 900MHz block (Zoomed)



- Average area increment over continuous sizing 6.78\%


## Leakage Power - 300MHz Block



## Leakage Power - 900MHz Block



## $\mathrm{V}_{\mathrm{T}}$ Selection - 300MHz Block (Delay 2250ps)



## $\mathrm{V}_{\mathrm{T}}$ Selection -900 MHz Block (Delay 750ps)



## TI Benchmark

- Clock Period: 2.032 ns
- 125,000 sizeable cells
- Process: 40nm
> Process corner
- Delay optimization $-125^{\circ} \mathrm{C} 0.9 \mathrm{~V}$
- Leakage optimization $-105{ }^{\circ} \mathrm{C} 1.05 \mathrm{~V}$


## Processing Steps

- Obtained verilog netlist from placed and routed design
- Flattened all positive unate, non-unate and complex gates
- Generated relative placement constraint for each flattened gate
$>$ Single row, multiple columns
- Updated component list in the .def file
- Read .def and legalize placement
- Route
- Extracted RC (wire load) for gate size selection


## Sizeable Gate List

These are NOT all power efficient cells ... but the "customer" used them ...

- INV
- ND2
- ND3
- ND4
- NR2
- NR3
- AOI21
- AOI22
- OAl21
- OAl22
- AOI31
- AOI32
- AOI33
- AOI211
- AOI222
- OAl31
- OAl222
- AOAl211
- OAOI211
- MAJI3


## Flattened Cells

| Cell | Structure |  | Transistor Count |  |
| :--- | :--- | :---: | :---: | :---: |
|  |  | Flattened | Industrial |  |
| xnor2 | nand2 + oai21 | 10 | 12 |  |
| xor2 | nor2 + aoi21 | 10 | 12 |  |
| xnor3 | xor2 + xnor2 | 20 | 22 |  |
| xor3 | xor2 + xor2 | 20 | 22 |  |
| xnor4 | xor2 + xor2 + xnor2 | 30 | 30 |  |
| xor4 | xor2 + xor2 + xor2 | 30 | 30 |  |
| mux2 | inv + aoi22 + inv | 12 | 12 |  |
| muxi2 | inv + aoi22 | 10 | 10 |  |
| mux3 | (inv + aoi22) + (inv + inv + oai22) | 22 | 20 |  |
| mux4 | (inv + aoi22) + aoi22 + (inv + oai22) | 28 | 26 |  |
| nand2B | inv + nand2 | 6 | 6 |  |
| nor2B | inv + nor2 | 6 | 6 |  |

## Flattened Cell Structure (Cont.)

| Cell | Structure | Transistor Count |  |
| :--- | :--- | :---: | :---: |
|  |  | Flattened | Industrial |
| ao2bb2 | nand2 + oai21 | 10 | 10 |
| oa2bb2 | nor2 + aoi21 | 10 | 10 |
| ao21b | nand2 + nand2 | 8 | 8 |
| mux2and2 | nand2 + inv + inv + oai22 | 16 | 14 |
| mux2or2B | inv + nor2 + inv + inv + oai22 | 18 | 16 |
| buf | inv + inv | 4 | 4 |
| or2 | nor2 + inv | 6 | 6 |
| an2 | nand2 + inv | 6 | 6 |
| or3 | nor3 + inv | 8 | 8 |
| an3 | nand3 + inv | 8 | 8 |
| or4 | nor2 + nor2 + nand2 | 12 | 12 |
| an4 | nand4 + inv | 10 | 10 |

## Flattened Cell Structure (Cont.)

| Cell | Structure | Transistor Count |  |
| :--- | :--- | :---: | :---: |
|  |  | Flattened | Industrial |
| or5 | nor3 + nor2 + nand2 | 14 | 14 |
| an5 | nand3 + nand2 + nor2 | 14 | 14 |
| or6 | nor2 + nor2 + nor2 + nand3 | 18 | 18 |
| an6 | nand3 + nand3 + nor2 | 16 | 16 |
| ao21 | aoi21 + inv | 8 | 8 |
| ao22 | aoi22 + inv | 10 | 12 |
| ao222 | aoi22 + nand2 + nand2 | 16 | 18 |
| ao2222 | aoi22 + aoi22 + nand2 | 20 | 24 |
| ao31 | aoi31 + inv | 10 | 10 |
| oa21 | oai21 + inv | 8 | 8 |
| oa22 | oai22 + inv | 10 | 10 |
| aoa211 | aoai211 + inv | 10 | 10 |
| oao211 | oaoi211 + inv | 10 | 10 |

## Flattened Cell Structure (Cont.)

| Cell | Structure | Transistor Count |  |
| :--- | :--- | :---: | :---: |
|  |  | Flattened | Industrial |
| nand3B | inv + nand3 | 8 | 8 |
| nor3B | inv + nor3 | 8 | 8 |
| addh | xor2 + and2 | 16 | 16 |
| addf | xor2, xor2, maji3, inv | 32 | 32 |
| addf42 | addf + addf | 56 | 56 |

## Continuous vs. Discrete Sizing Result



## $\mathrm{V}_{\mathrm{T}}$ Assignment

| $\mathrm{V}_{T}$ Type | Combinational <br> Gates | Registers |
| :--- | :---: | :---: |
| Extended High $\mathrm{V}_{\mathrm{T}}$ | $47 \%$ | $0 \%$ |
| High $\mathrm{V}_{\mathrm{T}}$ | $1 \%$ | $0 \%$ |
| Extended Standard $\mathrm{V}_{\mathrm{T}}$ | $37 \%$ | $100 \%$ |
| Standard $\mathrm{V}_{\mathrm{T}}$ | $14 \%$ | $0 \%$ |

## Results

- Performance

|  | Original <br> Base Line | Forge |
| :--- | :---: | :---: |
| Period (ps) | 1950 | 1768 |

- Power

|  | Original <br> Base Line | Forge |
| :--- | :---: | :---: |
| P_lkg comb (mW) | 95.4 | 29.3 |
| P_lkg_seq (mW) | 22.3 | 9.7 |
| Active_area (um) | 317375 | 212594 |

## Results (cont.)

|  | Original Base <br> Line | Forge |
| :--- | :---: | :---: |
| w_gates (um) | 317375 | 212594 |
| cell_count | 103494 | 125943 |
| L_horiz_wire (um) | 1400990 | 1434343 |
| L_vert_wire (um) | 1698424 | 1697836 |

## Power Optimal Cell Library

- INV
- NAND2
- NAND3
- NOR2
- NOR3
- AOI21
- AOI22
- OAl12
- OAl22
- Plus ONE D-FF for each $\mathrm{V}_{\mathrm{T}}$ !!!
- (Not counting scan-related cells ...)


## Power Optimal Cell Library (cont'd)

- INV
- NAND2
- NAND3
- NOR2
- NOR3
> Ok, only 9 sizeable cells
> Ah, but how many drive strengths?
> And how many beta ratios?
> Yeah, but what about the explosion in "global nets" with such "tiny" cells?
> Good questions ... we'll take them one at a time


## Our Base Standard Cell Library (LIB)

- IBM 130nm 1.2V 25C process technology
- Wn's in [0.28um, 7.84um], steps of 0.28um
- Wp's are any Wn times any of the beta ratios
- The full set of beta ratios $(\mathrm{Wp} / \mathrm{Wn})$ is:

- LIB is our full library and our objective is to find the smallest subset of these size and beta alternatives that yields similar power-delay curves


## Same Effective Beta Range for Other Gates

| GATE | $\boldsymbol{\beta}_{\min }$ | $\boldsymbol{\beta}_{\text {neutral }}$ | $\boldsymbol{\beta}_{\max }$ | Total Betas |
| :---: | :---: | :---: | :---: | :---: |
| INV | 0.8 | 2.8 | 6.0 | 15 |
| AOI21 | 0.8 | 2.8 | 6.0 | 16 |
| OAI21 | 0.8 | 2.8 | 6.0 | 16 |
| AOI22 | 0.8 | 2.8 | 6.0 | 15 |
| OAI22 | 0.8 | 2.8 | 6.0 | 15 |
| NAND2 | 0.4 | 1.4 | 3.0 | 15 |
| NOR2 | 1.0 | 5.6 | 12.0 | 15 |
| NAND3 | 0.26 | 1.0 | 2.2 | 14 |
| NOR3 | 1.0 | 8.4 | 18.0 | 15 |

$$
\begin{array}{|l|l|l|l|l|l|l|l|l|l|l|l|l|l|l|}
\hline 0.8 & 1.0 & 1.2 & 1.6 & 2.0 & 2.4 & 2.8 & 3.2 & 3.6 & 4.0 & 4.4 & 4.8 & 5.2 & 5.6 & 6.0 \\
\hline
\end{array}
$$

## Experimental Setup

- Synthesize benchmarks with the leading commercial synthesis tool using the full library (LIB)
$>$ With wire load model
- Generate the continuous power-delay curves for all benchmarks
$>$ Select three points on the continuous curve for each benchmark: min delay and two points in the "knee" of the curve
- Then plot beta density function

$$
\beta_{o p t}=\sqrt{\frac{M_{P} \mu_{N}}{M_{N} \mu_{P}}}
$$

## Beta Density Functions

Frequency


Frequency
Beta ratio


## Beta Density Functions (cont'd)



## Frequency



## Which Cell Sizes Should We Pick?

- Generate 5 test discrete libraries

1. LIB: full discrete library
2. GEO: Geometrically spaced Wn sizes: $0.28 u m, 0.56 u m, 1.12 u m, 2.24 u m, 4.48 u m$ along with all beta options $0.5 \mathrm{X}, 1 \mathrm{X}, 2 \mathrm{X}, 4 \mathrm{X}, 8 \mathrm{X}$ drives
3. LIN: Linearly spaced Wn sizes: $0.28 u m,[0.56 u m-2.24 \mathrm{um}]$ in steps of 0.56 um along with all beta options $\quad 0.5 \mathrm{X}, 1 \mathrm{X}, 2 \mathrm{X}, 3 \mathrm{X}, 4 \mathrm{X}$
4. 3SIGMA: LIN but with discrete betas restricted to $+/-3$ sigma of the mean beta computed for each gate
5. 1.5SIGMA: LIN but with discrete betas restricted to $+/-1.5$ sigma of the mean beta computed for each gate
$>$ Beta of 1 included in 3SIGMA and 1.5SIGMA for down sizing off critical paths
6. 1BETA: Linearly spaced as above but with a single beta ratio
$>$ Beta chosen as the closest to the computed mean beta

$$
\begin{array}{|l|l|l|l|l|l|l|l|l|l|l|l|l|l|l|}
\hline 0.8 & 1.0 & 1.2 & 1.6 & 2.0 & 2.4 & 2.8 & 3.2 & 3.6 & 4.0 & 4.4 & 4.8 & 5.2 & 5.6 & 6.0 \\
\hline
\end{array}
$$

## Library Beta Values

| Gate | 3SIGMA | 1.5SIGMA | 1BETA |
| :---: | :---: | :---: | :---: |
| INV | 0.81 .01 .21 .622 .4 | 1.01 .21 .62 .0 | 1.6 |
| NAND2 |  | 1.01 .21 .4 | 1.2 |
| NOR2 | 1.01 .62 .43 .24 .0 | 1.01 .62 .43 .2 | 2.4 |
| NAND3 | $\begin{array}{lllll} 0.6 & 0.7 & 0.86 & 1.0 & 1.16 \\ & 1.31 \\ & 1.46 & 1.61 \end{array}$ | 0.861 .01 .16 | 1.16 |
| NOR3 | 1.02 .43 .64 .8 | 1.02 .43 .6 | 2.4 |
| AOI21 | 0.81 .01 .62 .43 .2 | 1.01 .62 .4 | 1.6 |
| OAl21 | 0.81 .01 .21 .62 .02 .4 | 1.01 .21 .62 .0 | 1.6 |
| AO122 | 0.81 .01 .21 .62 .02 .4 | 1.01 .21 .62 .0 | 1.6 |
| OAl22 | 0.81 .01 .21 .62 .02 .4 | 1.01 .21 .62 .0 | 1.0 |

## Cell Count for Each Library

| Gate | Number of Cells |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | LIB | GEO | LIN | 3SIGMA | 1.5SIGMA | 1BETA |  |
| INV | 420 | 75 | 75 | 30 | 20 | 5 |  |
| NAND2 | 420 | 75 | 75 | 35 | 15 | 5 |  |
| NOR2 | 420 | 75 | 75 | 25 | 20 | 5 |  |
| NAND3 | 392 | 70 | 70 | 40 | 15 | 5 |  |
| NOR3 | 420 | 75 | 75 | 20 | 15 | 5 |  |
| AOI21 | 448 | 80 | 80 | 25 | 15 | 5 |  |
| OAI21 | 448 | 80 | 80 | 30 | 20 | 5 |  |
| AOI22 | 420 | 75 | 75 | 30 | 20 | 5 |  |
| OAI22 | 420 | 75 | 75 | 30 | 20 | 5 |  |
| TOTAL | 3808 | 680 | 680 | 265 | 160 | $\mathbf{4 5}$ |  |

## Benchmark b20 Mapped to LIB and GEO

- Map points on the continuous power-delay curves to each of the 6 libraries - LIB, GEO, LIN, 3SIGMA, 1.5SIGMA, and 1BETA
- Measure performance deviation with respect to LIB



## Benchmark b20 Mapped to LIB and LIN



## Benchmark b20 Mapped to LIB and 3SIGMA



## Benchmark b20 Mapped to LIB and 1.5SIGMA



## Benchmark b20 Mapped to LIB and 1BETA



## 40nm TI Process 1.0V 20k Cells



## Library Conclusions

- Very low skew gates and high skew gates are rarely selected
- 3SIGMA library consisting of drive strengths $0.5 \mathrm{X}, 1 \mathrm{X}, 2 \mathrm{X}, 3 \mathrm{X}$ and 4X and beta ratios within $\beta_{o p t} \pm 3 \sigma$ ( 265 cells)
> 14X smaller library compared to LIB
> $0.8 \%$ performance loss
- 1.5SIGMA library consisting of drive strengths $0.5 \mathrm{X}, 1 \mathrm{X}, 2 \mathrm{X}, 3 \mathrm{X}$ and 4 X and beta ratios within $\beta_{o p t} \pm 1.5 \sigma$ ( 160 cells)
> 25 X smaller library compared to LIB
> $1.5 \%$ performance loss
- 1BETA library consisting of drive strengths $0.5 \mathrm{X}, 1 \mathrm{X}, 2 \mathrm{X}, 3 \mathrm{X}$ and 4 X and a single beta ratio ( 45 cells)
$>24 \%$ increase in power
> $9.1 \%$ increase in delay


## Global Net Issue

- Cell grouping in placement effectively knocks out the would-be extra global nets


## Pass Transistor Logic (PTL)

- Pass transistor logic based cells should NEVER be in a standard cell library
- Provably no benefit whatsoever
- How so?
- Let's go on a short tour ...


## Pass Transistor Logic (PTL)

- Seemingly very efficient and fast for 2:1 multiplexors

- Only six transistors
- But, very poor layout efficiency, with several diffusion breaks
$>$ Standard cell width is considerably larger than it would be for a seriesparallel six-transistor gate


## Modern PTL

- Static timing analysis (STA) tools demand purely capacitive inputs
- The PTL MUX had to re-designed as follows:

- Now 12 transistors!
- Plus diffusion breaks and poor layout efficiency


## PTL MUX -- Closer Look

- Let's look at the encircled inverter-transmission gate pair



## Inverter T-Gate Pair

- The following two circuits are absolutely identical
- But, the red wire is of no use
- It can only be used to help pull down the output by passing the 0 (gnd) through the pMOS (with gate input S), which is not effective (easily verified)
- Similarly for the pull up case



## PTL MUX

- Equivalence:



## PTL MUX (cont'd)

- Equivalence:

- With the red wire, it is an AOl22 gate
- But, is the red wire needed?


## PTL MUX (cont'd)

- Equivalence:

- But, is the red wire needed?
- No, if the inputs are re-ordered!
- If $A=B=0$, OUT should be 1 anyway


## PTL MUX is EXACTLY an AOI22 Gate!!

- Equivalence:

- Much less layout area
- Can easily add an output inverter to both if desired
- Conclusion: DO NOT PUT EXPLICIT PTL MUX IN THE LIBRARY


## Ok, but what about PTL XOR?



- But, need to have inputs with a purely capacitance load to enable static timing analysis


## Revised PTL XOR



## Closer Look at the PTL XOR



- Tri-state inverters are encircled


## PTL XOR Equivalence



## PTL XOR Equivalence - Inputs Reordered



## PTL XOR Equivalence - Inputs Reordered



## PTL-Summary

- PTL MUX is EXACTLY this:

- AOI22 plus inverters
- PTL XOR is EXACTLY this:

- AOI22 plus inverters


## XOR Implementation

- But, AOI22-based XOR has 12 transistors plus 2 diffusion breaks, so a cell width equivalent to 16 transistors
- NAND2-AOI12 XOR has 10 transistors, no breaks ... so it wins!!



## Full Adders

- The most area efficient adder:
- 28 transistors (for non-inverted carry and sum)
- 4 sizeable gates



## Full Adders (cont'd)

- The fastest full adder:
- 2 XOR's and NAND-based carry (3 NAND2's and one NAND3)
- 38 transistors
- 8 sizeable gates



## Full Adders (cont'd)

- The best full adder?
- 2 XOR's and mirror-carry
- 32 transistors
- 9 sizeable gates

FA


## Different 4:2 Implementations



## Comparison of Multiplier Implementations



## Full Adders

- The clear winner:
- 2 XOR's and mirror-carry
- 32 transistors
- 9 sizeable gates

FA


## Why So Much Energy Waste? (cont'd)

- Many digital blocks include appreciable digital signal processing and/ or arithmetic networks
- You have to make sure there are no carry-ripple delays and you have to make sure the compression trees use minimum power
- The latter requires the most power efficient full adder cell
- And one that is very "friendly" in gate size selection
- The leading commercial tools do not hit the mark here ...


## Generalized Carry-Save (GCS) Arithmetic

- DSP networks are largely an interconnection of adders, multipliers
$>$ Rippling of carries must be systematically avoided in arithmetic calculations
$>$ The carry operation is serial and thus many mathematical operations cannot be done in parallel
$>$ We have recently developed Generalized Carry-Save (GCS), which is a technique to parallelize addition and multiplication
$>$ All bits are added in parallel (essentially 4:2 compression) and in multiplication only the compression of partial products is employed

- Adder delay is therefore independent of operand widths
- Multiplier delay only depends on the logarithm of the multiplier width


## A Multiplier and Adder Network



Carry-free compression to 2 final rows, whose addition equals "out"

## Generalized Carry-Save Arithmetic for IIR



$$
y(n)=C_{1} * y(n-1)+C_{2} * y(n-2)+x(n)
$$

## 4:2 Compression



- Cout does not depend on Cin


## Ripple-Free 4:2 Compressor



## Ripple-Free 6:2 Compressor



## Sum of 16 16b vectors - TI 45nm 0.9V



## Nvidia FMA Example - TI 45nm 0.9V



## Why Do People Worry About Min-Delay?

- No, really, why do people worry about min-delay (hold time)??
- Let's consider the problem:

- Consider the "hold" for the $i^{\text {th }}$ capturing event in the $2^{\text {nd }}$ bank of DFFs
- This "races" with the $(i+1)^{\text {st }}$ capturing event in the $1^{\text {st }}$ bank of DFFs

$$
\phi_{i+1}+T_{c l k->Q}+T_{C L \min }-T_{\text {skew }}>\phi_{i+1}+T_{\text {hold }}
$$

- Thus:

$$
T_{C L \min }>T_{\text {hold }}-T_{\text {clk } \rightarrow Q}+T_{\text {skew }}
$$

## Min-Delay?



- For contemporary DFFs, $T_{\text {hold }}$ is negative and roughly two gate delays

$$
T_{s u} \approx\left|T_{\text {hold }}\right|
$$

- So, in the absence of clock skew, $T_{\text {CLmin }}$ is negative by 4 gate delays!!!
- You mean to tell me clock skew (in the worst case) is WAY more than 4 gate delays??
\gg> 4 gate delays?? (Now there's a problem the CAD industry hasn't addressed!!)


## Min-Delay (cont'd)



So, in the absence of clock skew, $T_{\text {CLmin }}$ is negative by 4 gate delays!!! You mean to tell me clock skew (in the worst case) is WAY more than 4 gate delays??
> The good news is that our gate size selection tool (Forge) is able to identify the optimal points in the network to add delay (buffers) to satisfy any desired $T_{\text {CLmin }}$
> And minimizes total area (and power) added in the process

## Energy Cost for Margins (Energy Margins)



- Many today argue there is a HUGE energy cost for margins
$>$ So they say we need to go to asynchronous, software that tolerates errors, etc.
> But they ignore the 4-100X overheads there ...
- Definitely can substantially LOWER your energy cost for margin


## Ongoing Work

- Still more work on defining the optimal synthesis library
- Major new initiative: adding analysis of local statistical variations into the power optimization


## Conclusion

- Goal: Toward optimal power efficiency in digital IC's
- Message: Existing tools and libraries leave a LARGE amount of energy on the table
- Conclusion: We have devised means that seek to take a fair amount of that energy off the table

